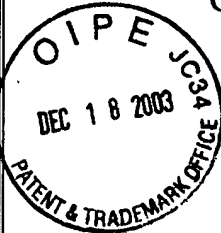










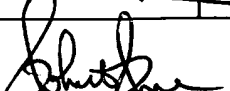
INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)				ATTY. DOCKET NO. 005917 USA/FET/FET		SERIAL NO. 09/998,372	
				APPLICANT Young Joseph PAIK			
				FILING DATE November 30, 2001		GROUP 3723	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
RR	4,207,520	06/10/80	Flora et al.			04/06/78	
	4,209,744	06/24/80	Gerasimov et al.			03/27/78	
	4,609,870	09/02/86	Lale et al.			09/13/84	
	4,755,753	07/05/88	Chern			07/23/86	
	5,427,878	06/27/95	Corliss			05/16/94	
	5,534,289	07/09/96	Bilder et al.			01/03/95	
	5,867,389	02/02/99	Hamada et al.			11/26/96	
	6,041,263	03/21/00	Boston et al.			10/01/97	
	6,077,412	06/20/00	Ting et al.			10/30/98	
	6,271,670	08/07/01	Caffey			02/08/99	
	6,400,162	06/04/02	Mallory et al.			07/21/00	
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RR	6,587,744	07/01/03	Stoddard et al.			06/20/00	
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
RR	WO 01/11679	02/15/01	WIPO			X	
RR	WO 01/080306	10/25/01	WIPO			X	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
RR	Miller, G. L., D. A. H. Robinson, and J. D. Wiley. July 1976. "Contactless measurement of semiconductor conductivity by radio frequency-free-carrier power absorption." <i>Rev. Sci. Instrum.</i> , Volume 47, No. 7. pp. 799 - 805.						
RR	1999. "Contactless Bulk Resistivity/Sheet Resistance Measurement and Mapping Systems." www.Lehighton.com/fabtech1/index.html .						
RR	2000. "Microsense II Capacitance Gaging System." www.adetech.com .						
EXAMINER 				DATE CONSIDERED 3/29/04			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)  RECEIVED DEC 23 2003 TECHNOLOGY CENTER R3700				ATTY. DOCKET NO. 005917 USA/FET/FET		SERIAL NO. 09/998,372	
				APPLICANT Young Joseph PAIK			
				GROUP 3723			
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation Yes No	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
CB	El Chemali, Chadi et al. July/August 2000. "Multizone uniformity control of a chemical mechanical polishing process utilizing a pre- and postmeasurement strategy." <i>J. Vac. Sci. Technol.</i> Volume 18, No. 4. pp. 1287 – 1296.						
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	"ADE Technologies, Inc. – 6360." http://www.adetech.com/6360.shtml .						
V	"3D optical profilometer MicroXAM by ADE Phase Shift." http://www.phase-shift.com/microxam.shtml .						
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				APPLICANT Young Joseph PAIK			
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U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
   	4,901,218	02/13/90	Cornwell			03/04/88	
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CITATION IN AN
APPLICATION**

(PTO-1449)



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005917 USA/FET/FET

SERIAL NO.
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APPLICANT
Young Joseph PAIK

FILING DATE
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GROUP

FOREIGN PATENT DOCUMENTS

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						Yes	No
BB	0 397 924 A1	11/22/90	Europe			X	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

BB	Rocha, Joao and Carlos Ramos. September 12, 1994. "Task Planning for Flexible and Agile Manufacturing Systems." <i>Intelligent Robots and Systems '94. Advanced Robotic Systems and the Real World, IROS '94. Proceedings of the IEEE/RSJ/GI International Conference on Munich, Germany 12-16 Sept. 1994.</i> New York, New York: IEEE. pp. 105-112.
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	March 29, 2002. Office Action for U.S. Serial No. 09/363,966, filed July 29, 1999.
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